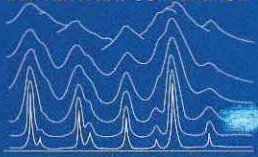


THE DENVER X-RAY CONFERENCE

**64th Annual
Conference on
Applications of
X-ray Analysis**

DENVER X-RAY CONFERENCE®



CALL FOR PAPERS

The DXC invites papers in all areas of X-ray analysis. The size and congeniality of the conference make it ideal for presenting your work, interacting with colleagues, and seeking the advice of experts.

3 – 7 August 2015

The Westin Westminster,
Westminster, Colorado, U.S.A.

Joint Conference with the 16th
International Conference on Total
Reflection X-ray Fluorescence Analysis
and Related Methods (TXRF 2015)

DEADLINE FOR
SUBMISSION OF
ABSTRACTS
6 March 2015

TXRF2015



0160091646275

*Plenary Session:
TXRF Around the World*

Sponsored by



SPECIAL SESSIONS

Wednesday, Thursday & Friday

Session titles, chairs and invited speakers listed below:

SPECIAL TOPICS IN X-RAY ANALYSIS

New Developments in XRD & XRF Instrumentation

Chairs:

T. Fawcett, T. Blanton, ICDD, Newtown Square, PA
fawcett@icdd.com; tblanton@icdd.com

Abstracts should be submitted by technical representatives of a manufacturer. They should discuss specifications and applications concerning one of their newest and most important products. Talks should include comments about software, XRD and XRF equipment, and accessories. Prices or comparisons of competitors' products can not be included.

Characterization of Nanomaterials

Chair:

I.C. Noyan, Columbia University, New York, NY
icn2@columbia.com

Invited speakers to be announced.

Energy Materials

Chair:

M.A. Rodriguez, Sandia National Laboratory, Albuquerque, NM
marodri@sandia.gov

Probing Energy Materials with High Energy X-rays

K. Chapman, APS – Argonne National Laboratory, Argonne, IL

Cement and Related Construction Materials

Chair:

D. Broton, Construction Technology Labs, Skokie, IL
dbroton@ctlgroupp.com

X-ray Diffraction & Beyond

J. Anderson, PANalytical, Westborough, MA

Cultural Heritage

Chair:

M. Delgado, University de Los Andes, Merida, Venezuela
migueld@ula.ve

Invited speakers to be announced.

TXRF Sessions

Chairs and invited speakers to be announced.

- SR-TXRF
- TXRF Semiconductor
- TXRF Environmental
- TXRF Art/Archeology
- TXRF Biological
- TXRF General Session

Abstracts are hereby solicited for oral presentations in any of the special sessions listed, or the XRD & XRF general sessions. Abstracts are also being solicited for the XRD and XRF poster sessions. Poster sessions will be held on Monday (XRD) and Tuesday (XRF & TXRF) evening of conference week, in conjunction with the evening receptions.

Abstracts are submitted online. Please visit our website for abstract preparation guidelines and submission instructions: www.dxcicdd.com. Please also monitor our web site regularly for updates to the Technical Program.

XRD

Stress Analysis

Chair:

T.R. Watkins, Oak Ridge National Laboratory, Oak Ridge, TN
watkinstr@ornl.gov

Microstructural and Residual Stress Behavior in an Additively Manufactured Shape Memory Alloy

A.S. Wu, Lawrence Livermore National Laboratory, Livermore, CA

Ptychography/Coherent Diffraction Imaging

Chair:

M.V. Holt, Center for Nanoscale Materials, Argonne National Lab, Argonne, IL, mvholt@anl.gov

High-resolution Biological Cryo-ptychography

D. Vine, APS - Argonne National Laboratory, Argonne, IL

XRF

Quantitative Analysis

Chair:

L.L. Brehm, Dow Chemical Company, Midland, MI, llbrehm@dow.com

Multimineral and Porosity Modeling using High-resolution XRF Core Scanning Technology

W. Ingram, Weatherford Labs, Golden, CO

Seed Treatment Active Loadings and Single Seed Screening by X-ray Fluorescence

W.W. Brubaker, DuPont Corporate Center for Analytical Sciences, Wilmington, DE

Fusion & Industrial Applications of XRF

Chairs:

J. Anzelmo, Anzelmo & Associates, Inc., Madison, WI
jaanzelmo@aol.com

M. van der Haar, PANalytical, Westborough, MA
marco.van.der.haar@panalytical.com

Quantitative Elemental Analysis of Difficult Materials by XRF using a Unique Fusion Sample Preparation Method

D. Aeschliman, 3M, Maplewood, MN

Extremely Bright: The Future of X-ray Analysis

Chair:

S. Vogt, X-ray Science Division, Argonne National Lab, Argonne, IL
svogt@aps.anl.gov

Title to be announced

T. Buonassisi, MIT, Photovoltaic Research Laboratory, Cambridge, MA

Defect Analysis at the Atomic Scale

F. Hofmann, Department of Engineering Science, University of Oxford, Oxford, United Kingdom

X-ray Imaging of Whole Catalyst Particles – Prospects and Challenges

F. Meirer, Department of Chemistry, Utrecht University, Utrecht, The Netherlands

Applied Materials

Chairs:

T. Fawcett, T. Blanton, ICDD, Newtown Square, PA
fawcett@icdd.com; tblanton@icdd.com

Invited speakers to be announced.

Rietveld

Chair & Invited speakers to be announced.

General XRD

Chair:

C. Murray, IBM T.J. Watson Research Center, Yorktown Heights, NY
conal@us.ibm.com

► Welcoming abstracts in all areas of X-ray diffraction and related techniques.

Environmental & Geological Applications

Chairs:

R. Van Grieken, University of Antwerp, Antwerp, Belgium
rene.vangrieken@uantwerpen.be

J. Miranda, Universidad Nacional Autónoma de México, México
miranda@fisica.unam.mx

Characterization of Particulate Air Pollution in Kingston, Jamaica

J. Boman, University of Gothenburg, Department of Chemistry & Molecular Biology, Göteborg, Sweden

Total Reflection X-ray Fluorescence as a Tool for Unveiling Solute Source in Streams during a Rain Episode

C. Vázquez, University of Buenos Aires, Buenos Aires, Argentina

PIXE as a Screening Technique for Consumer Products

G.F. Peaslee, Hope College, Holland, MI

Micro XRF

Chair:

G.J. Havrilla, Los Alamos National Laboratory, Los Alamos, NM
havrilla@lanl.gov

Confocal Micro-XRF Analysis for Monitoring Chemical Reactions

K. Tsuji, Osaka City University, Osaka, Japan

General XRF

Chair:

U. Fittschen, Washington State University, Pullman, WA
ursula.fittschen@wsu.edu

A Bright Future without High X-ray Brilliance: Applications of Modern Laboratory-Based XAFS

G. Seidler, University of Washington, Seattle, WA

Understanding Material Structure and Performance with 3D X-ray Imaging

B. Patterson, Los Alamos National Laboratory, Los Alamos, NM

► Welcoming abstracts in all areas of X-ray fluorescence and related techniques.

Deadline for submission of abstracts: 6 March

WORKSHOPS Monday & Tuesday

Please visit our website for a description of each workshop and a list of instructors.

XRD

Stress
Ptychography/Coherent Diffraction Imaging
Rietveld – Full Day
Basic to Advanced XRD Material Analysis – Full Day
Neutron Diffraction

XRF

XRF Sample Preparation
Basic XRF
Quantitative Analysis – Full Day
Micro XRF
Energy Dispersive XRF
Uncertainty in XRF

International TXRF 2015

Introduction to TXRF
TXRF Accreditation/Standardization

2015 DATES TO REMEMBER

Exhibit space opens	February
Deadline for submission of abstracts	6 March
Conference Program available on-line	May
Deadline to submit for Cohen Student Award	1 June
Deadline to submit for Robert L. Snyder Student Award	1 June
Deadline for Pre-registration discount fee	1 July
Deadline to apply for a Student Room	1 July
Deadline to book host hotel room at conference rate	20 July
Deadline for submission of manuscripts	10 September

REGISTRATION FEES

Please see our website for registration and cancellation policies.

	by 1 July	after 1 July
Full week: exhibits, workshops, sessions*	\$650	\$725
Monday & Tuesday: exhibits, workshops*	\$600	\$675
Wednesday, Thursday & Friday: exhibits, sessions*	\$600	\$675
Session Organizer, invited speaker & workshop instructor*	\$200	\$200
Student (I.D. required), Unemployed, 65 and older	\$275	\$350

* Includes a copy of Volume 59, *Advances in X-ray Analysis*, on CDROM.

Also on our website: Hotel and Travel Details, Student Housing, Awards & Grants, Exhibits/Sponsorships, Conference Proceedings and Registration.

www.DXCICDD.com